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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re patent application of

Dean et al.

Serial No. 09/394,302 Group Art Unit: 2184

Filed: September 10, 1999 Examiner: C. McGrath

For: BUILT-IN APPLICATION SPECIFIC INTEGRATED CIRCUIT IN-TRANSIT TEST SYSTEM

Assistant Commissioner of Patents
Washington, D.C. 20231

AMENDMENT UNDER 37 C.F.R. §1.111

Sir:

In response to the Office Action mailed September 4, 2002, please amend the above-identified patent application as follows:

IN THE SPECIFICATION:

Page 7, lines 12-19, please replace with the following paragraph:

FIG. 4(a) illustrates more details about test stimuli generator 34 and control device 31 in FIG. 3. Test stimuli generator 34 is a source of test patterns, such as built in self test (BIST) engine 42 and seed patterns 43. Control device 31 includes MUX 40, exclusive NOR (XNOR) checker/comparator 41, golden chip 37, test control register (TCR) mask 48, and status indicator 44. BIST engine 42 uses the seed patterns 43 to produce the test stimuli. The number of XNOR checker/comparators 41a to 41m, is equal to the number of outputs m each chip has, as shown in FIG. 4b. Each XNOR checker/comparator 41a-41m, is n-way, where n is the number of sockets for holding chips to be tested.
